

---

# Feedforward Active Substrate Noise Cancelling Technique using Power Supply $di/dt$ Detector

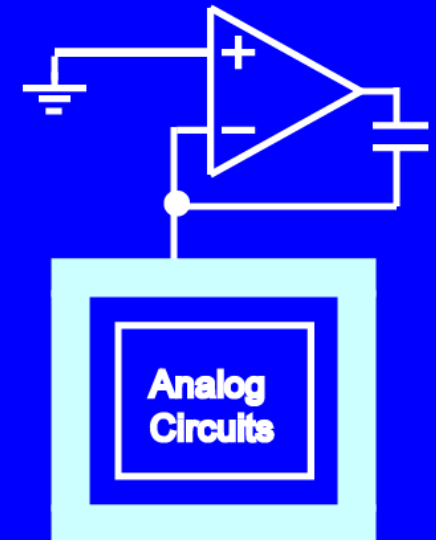
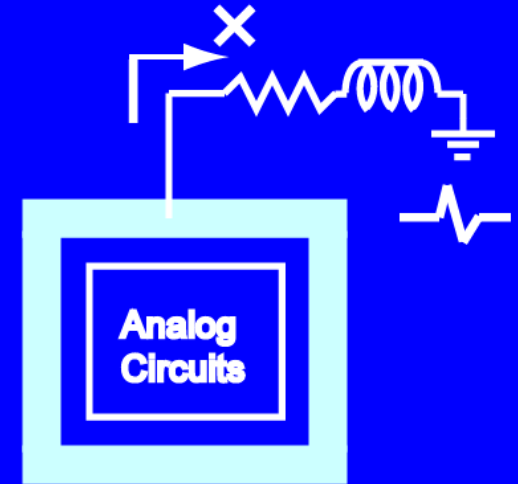
Toru Nakura<sup>#</sup>, Makoto Ikeda<sup>\*</sup>, Kunihiro Asada<sup>\*</sup>



*<sup>#</sup>Dept. of Electronic Engineering,  
<sup>\*</sup>VLSI Design and Education Center,  
University of Tokyo, Tokyo, Japan*

# Background -- Substrate Noise

- **Guard ring**
  - Parasitic inductance prevents the absorption
  - Noisy ground could increase the substrate noise
- **Self-detect and dynamic**
  - Feedback system
    - low bandwidth, unstable



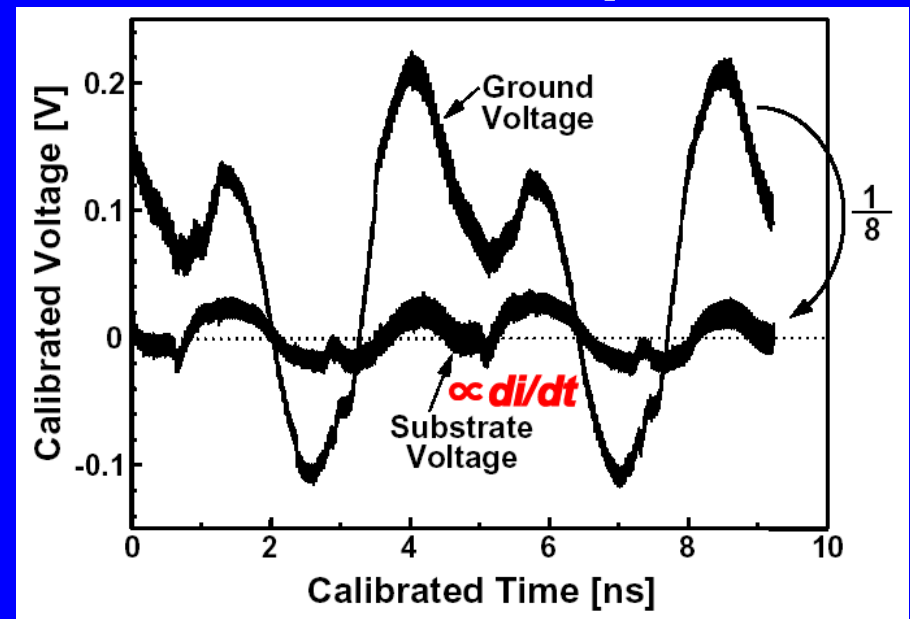
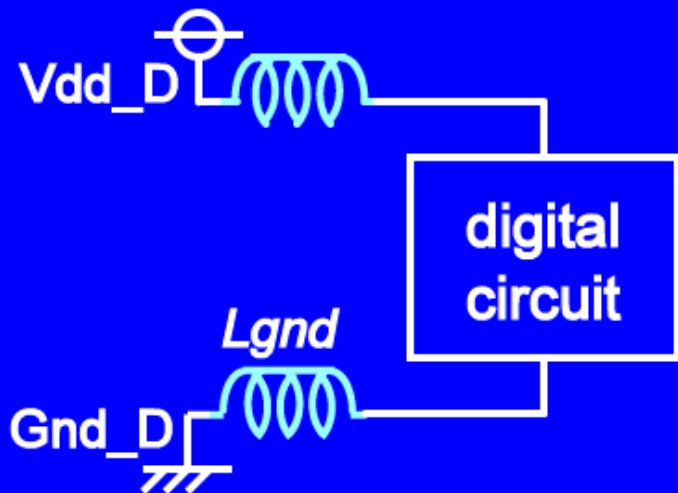
# Contents

---

- **Feedforward active substrate noise cancelling technique using a di/dt detector**
- **Substrate noise probing**
- **Measured substrate noise waveforms with the active cancelling ON/OFF**
- **Summary**

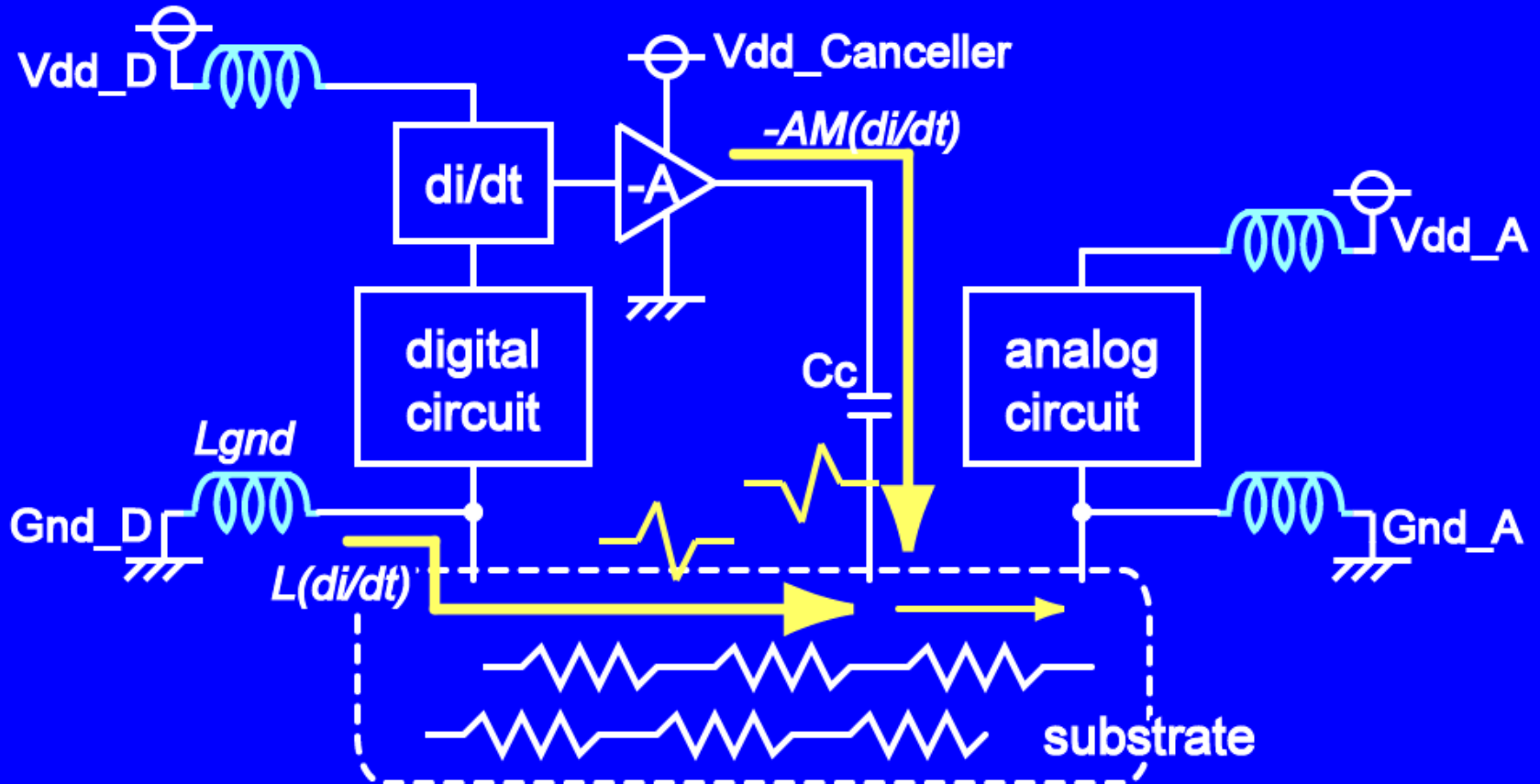
# Substrate Noise $\propto di/dt$

- Gnd noise is proportional to  $di/dt$ 
  - Inductance is dominant in  $Z_{gnd}$
- Gnd/substrate noise have the same shape
  - Gnd and substrate is tied with low impedance



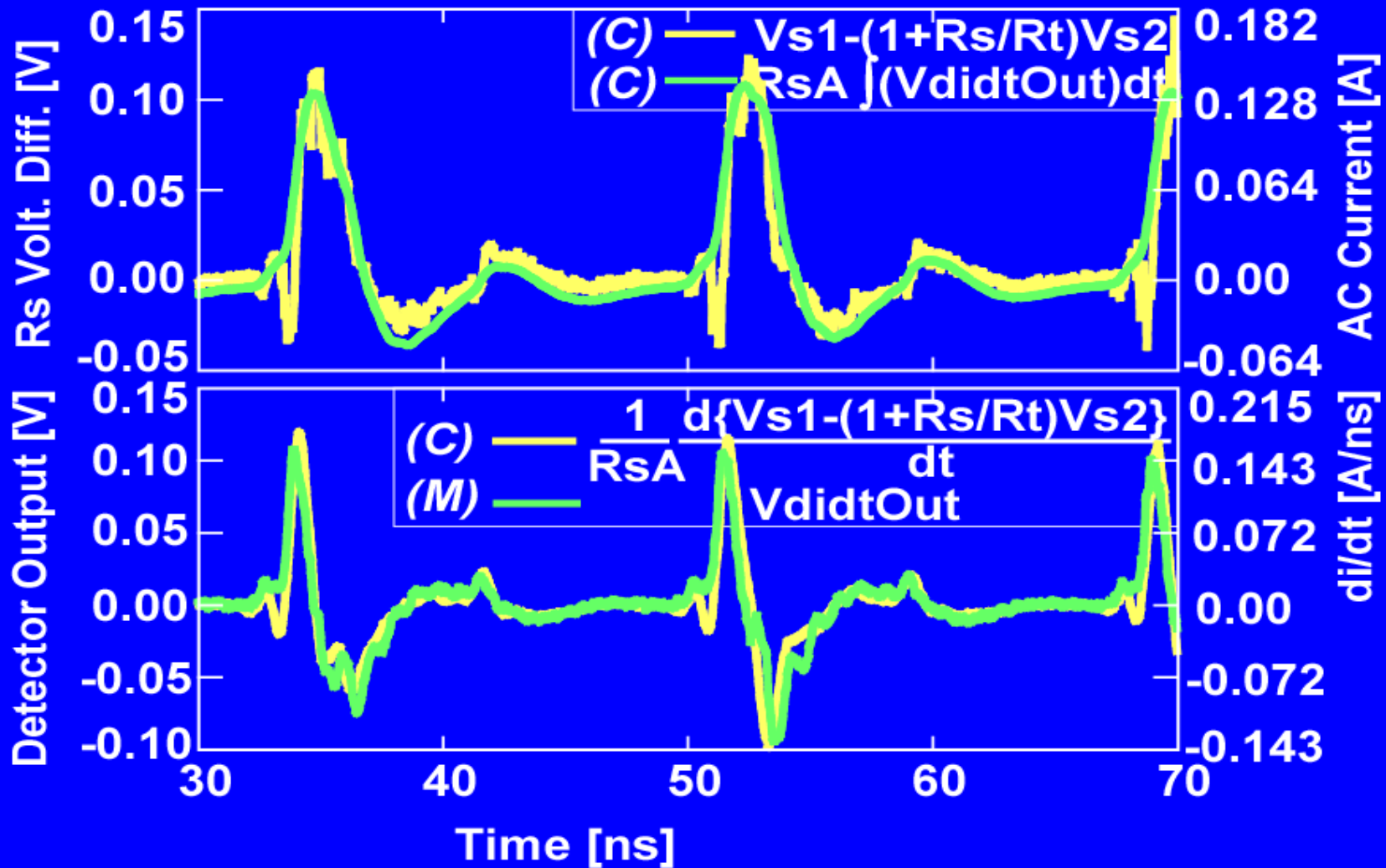
# F.F. Active Noise Cancelling

- $di/dt$  detector makes anti-phase signal  
no feedback  $\rightarrow$  stable, high bandwidth



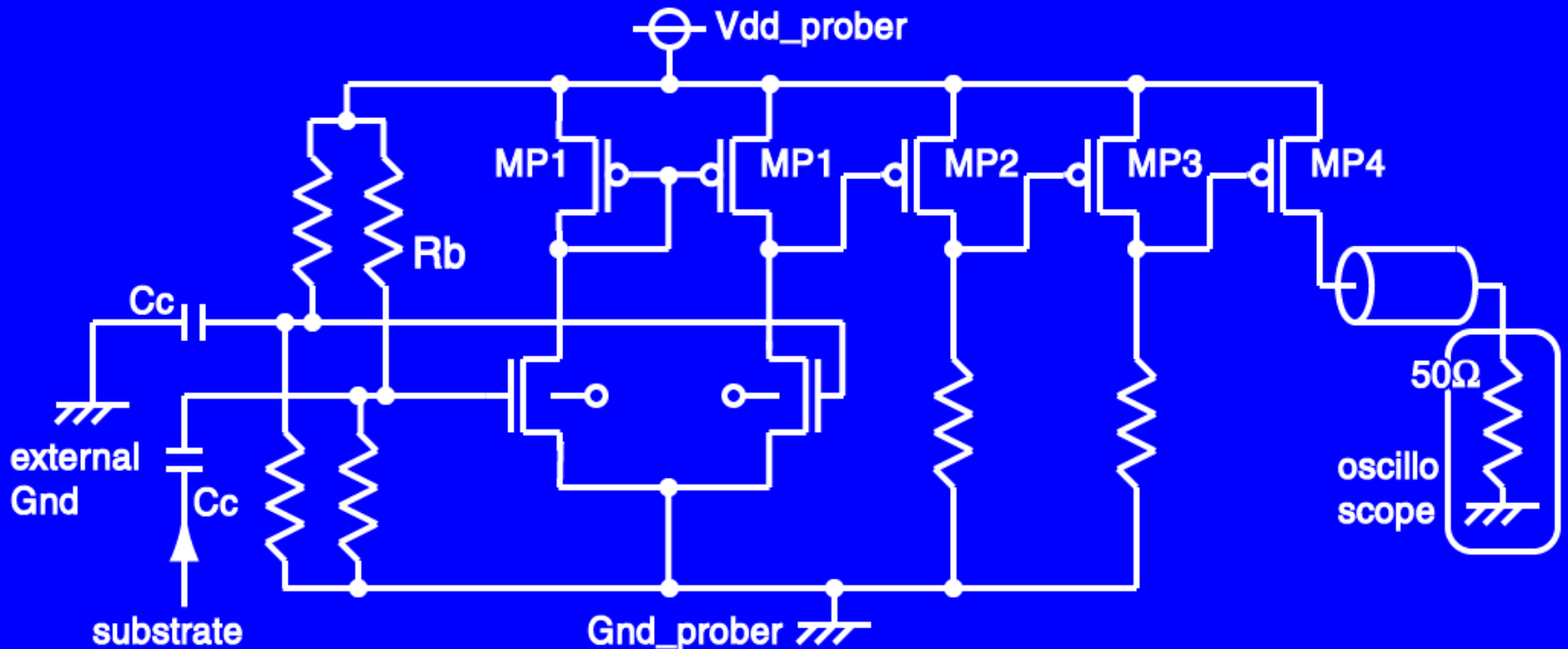


# di/dt Waveforms



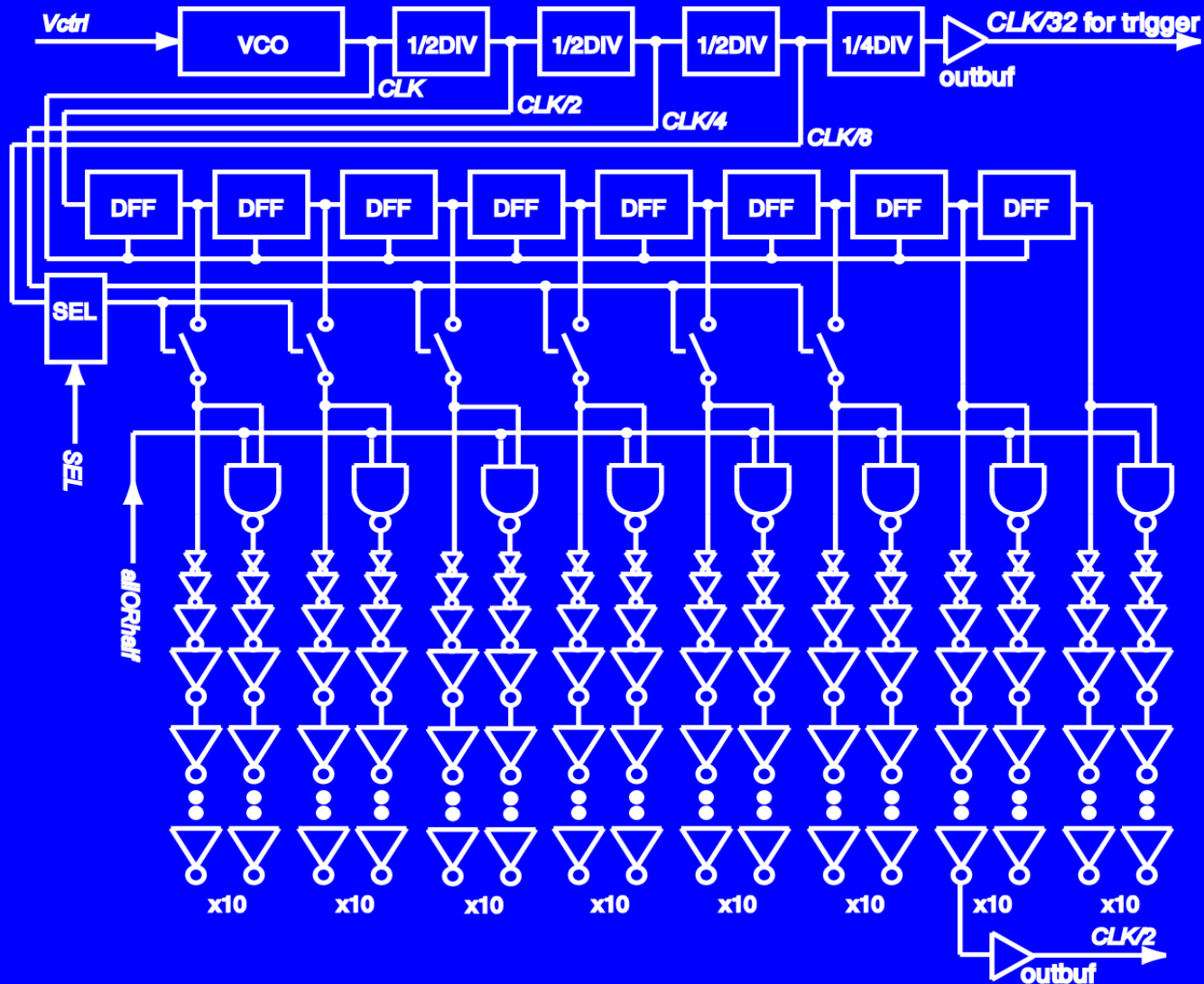
# Noise Probing for Verification

- Differential amplifier connected to the substrate and the external Gnd
- No body contact for NMOS



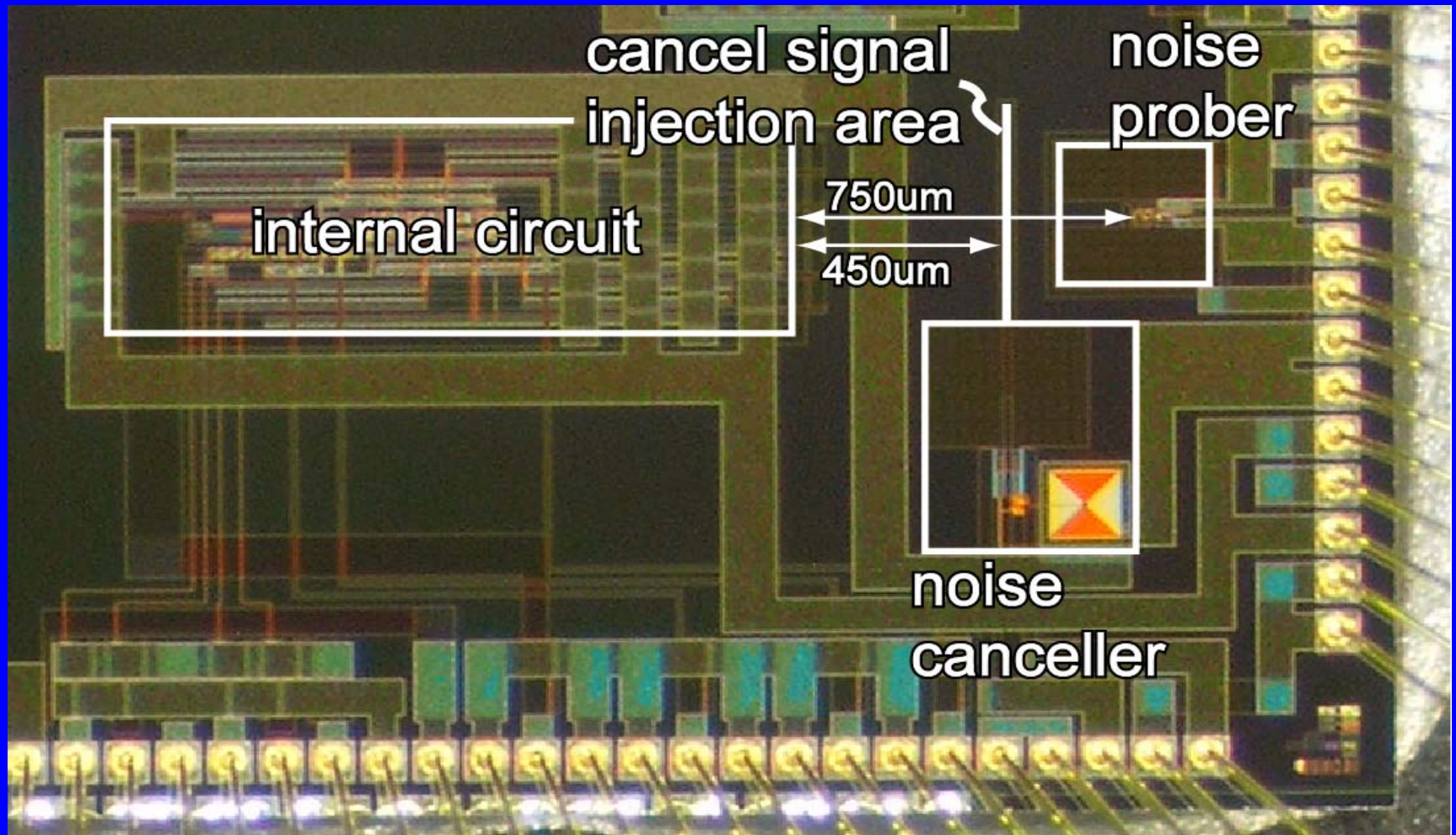


# Internal Circuit as Noise Source



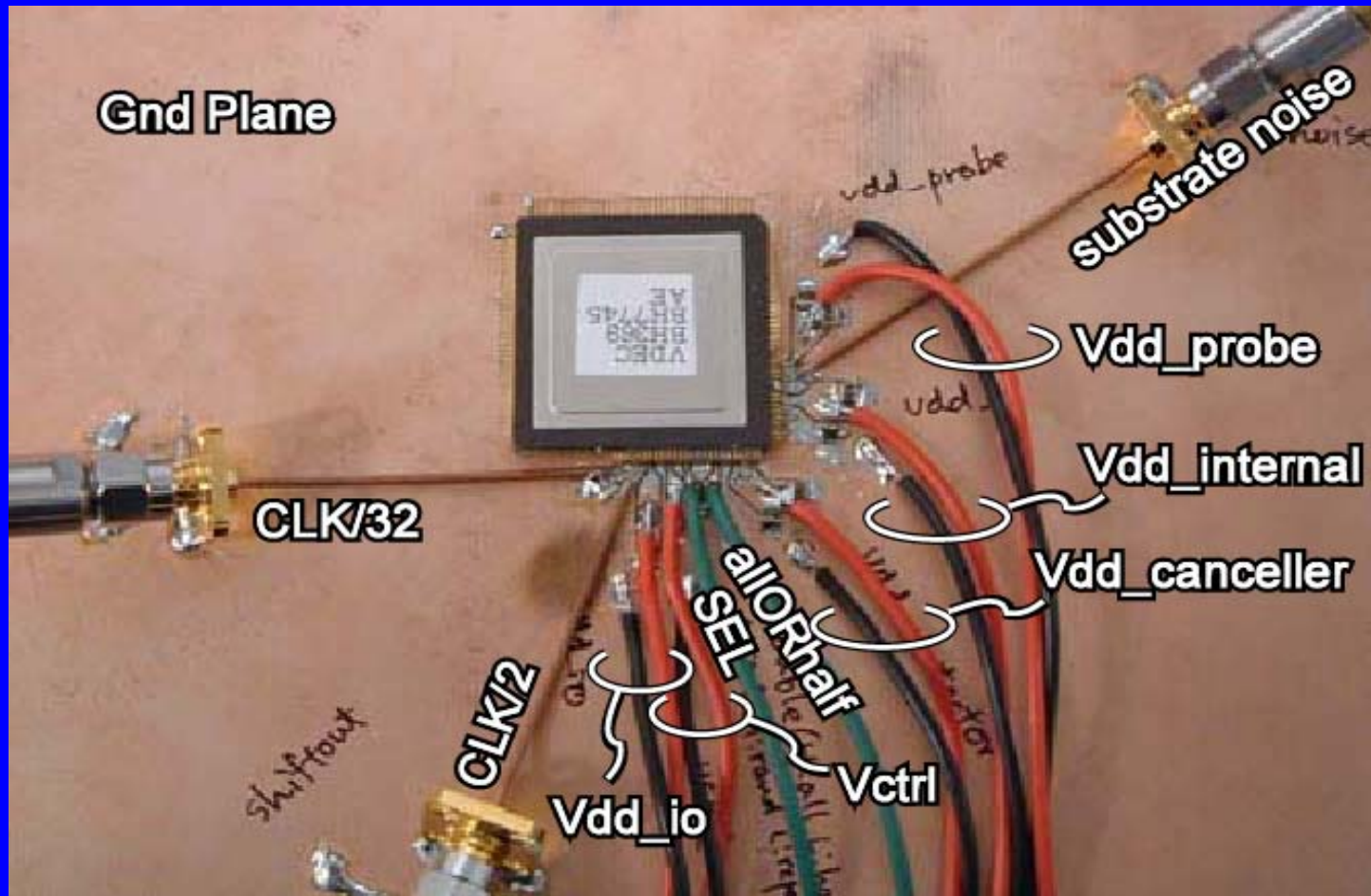
# Chip Photograph & Floor Plan

- 0.35 $\mu$ m 3ML 2P CMOS (3.0mm x 1.8mm)

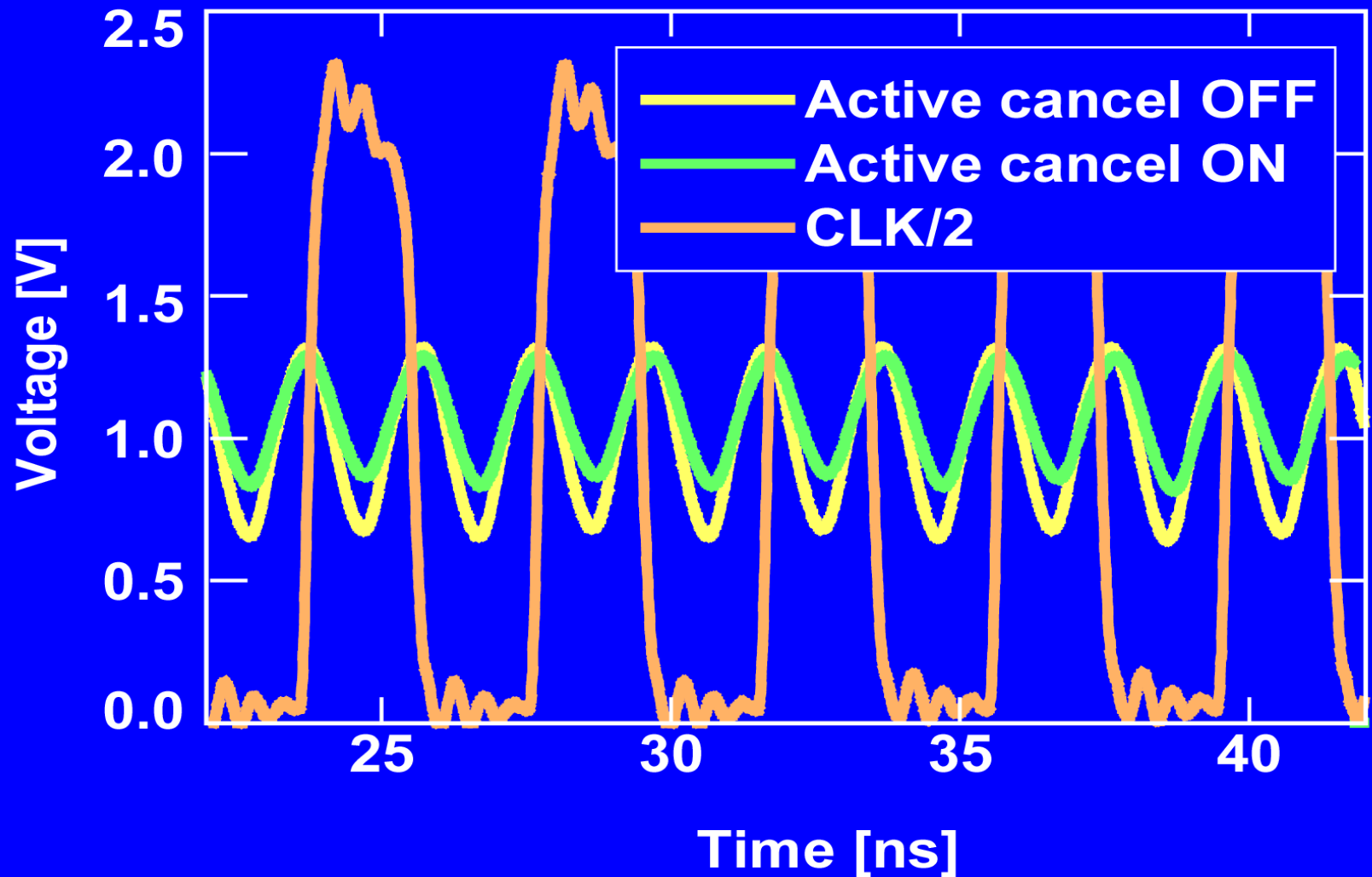


# Measurement Setup

- The test chip is mounted on a Cu board



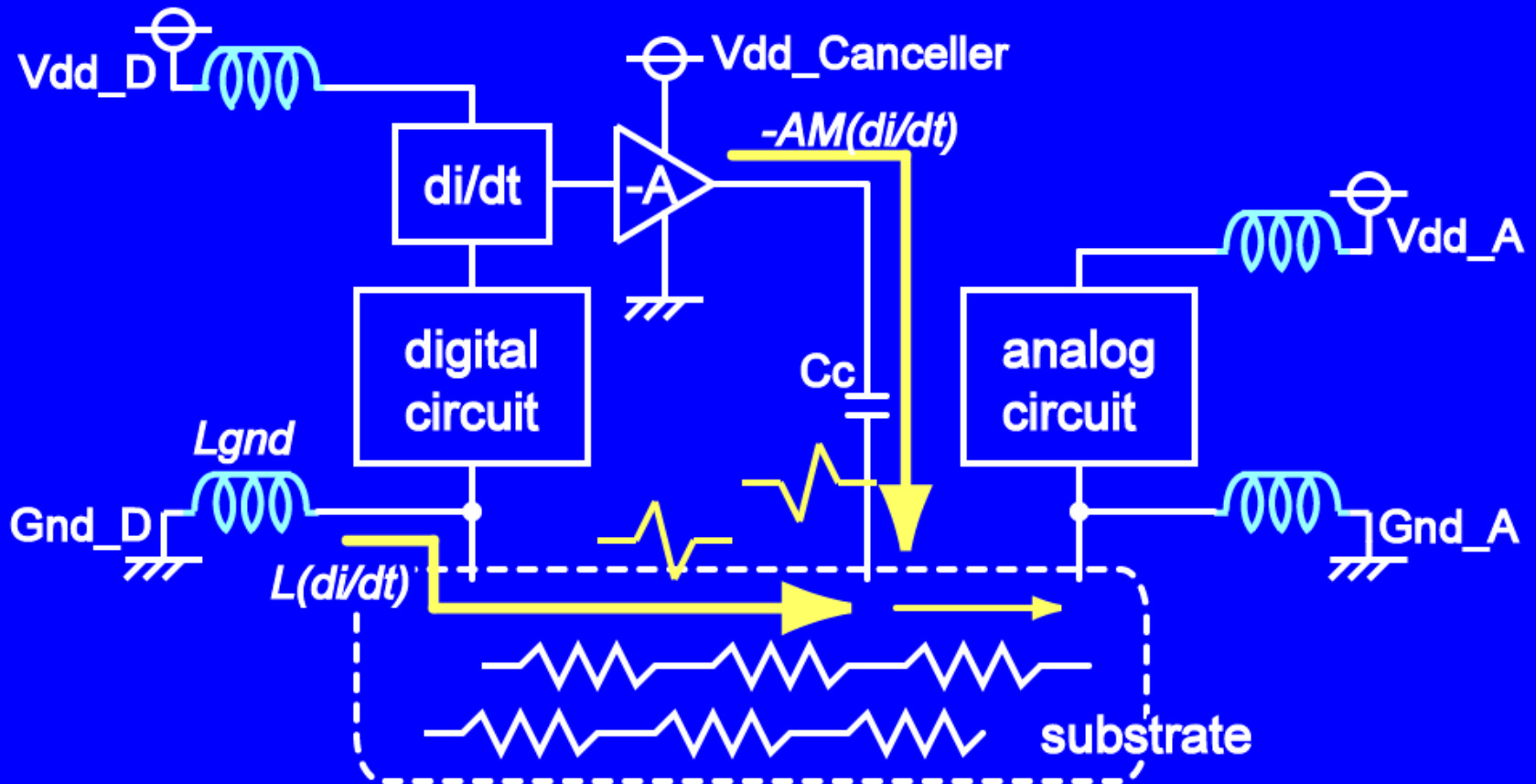
# Waveform (Repeat@500MHz)



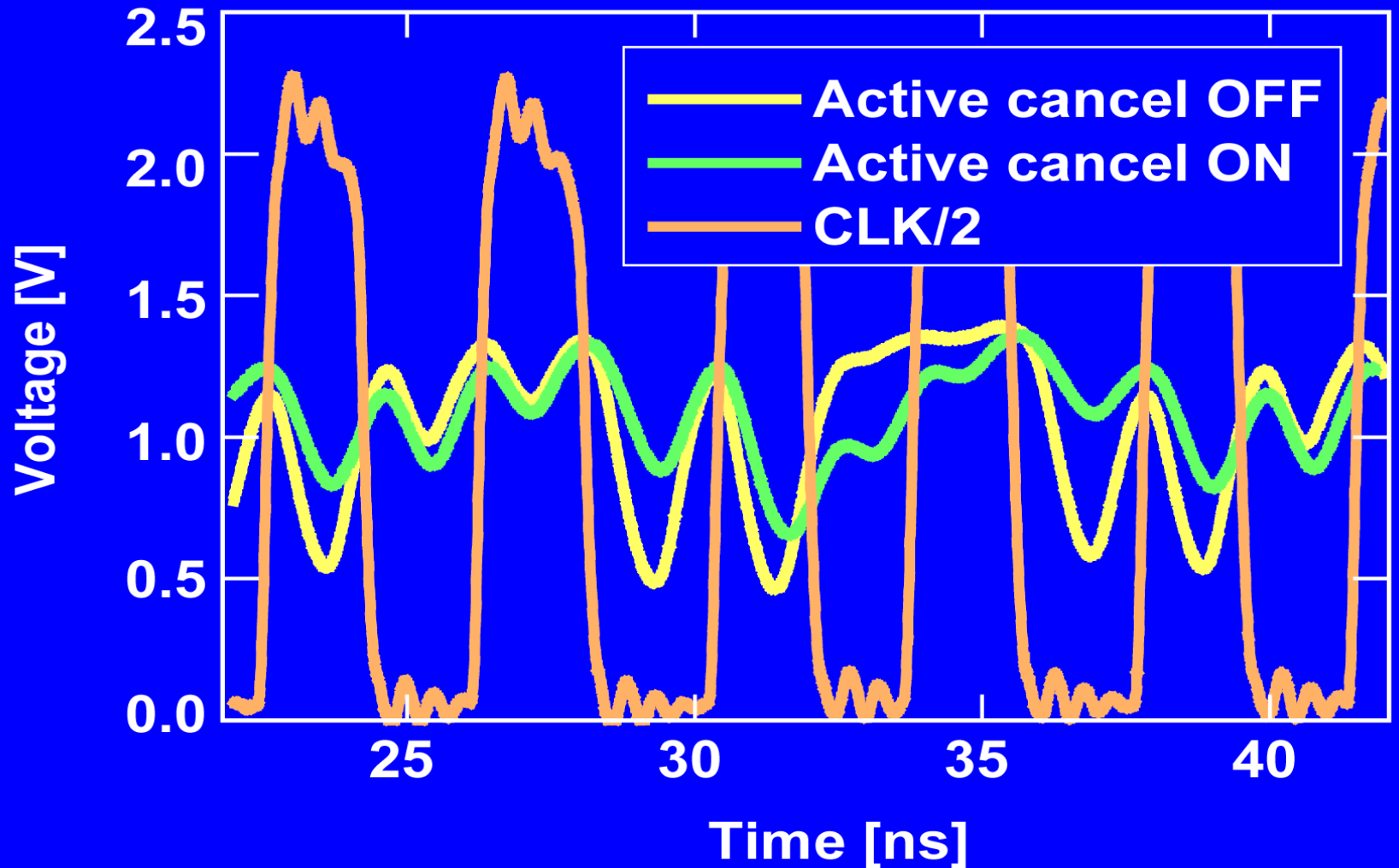


# Active Cancel ON/OFF

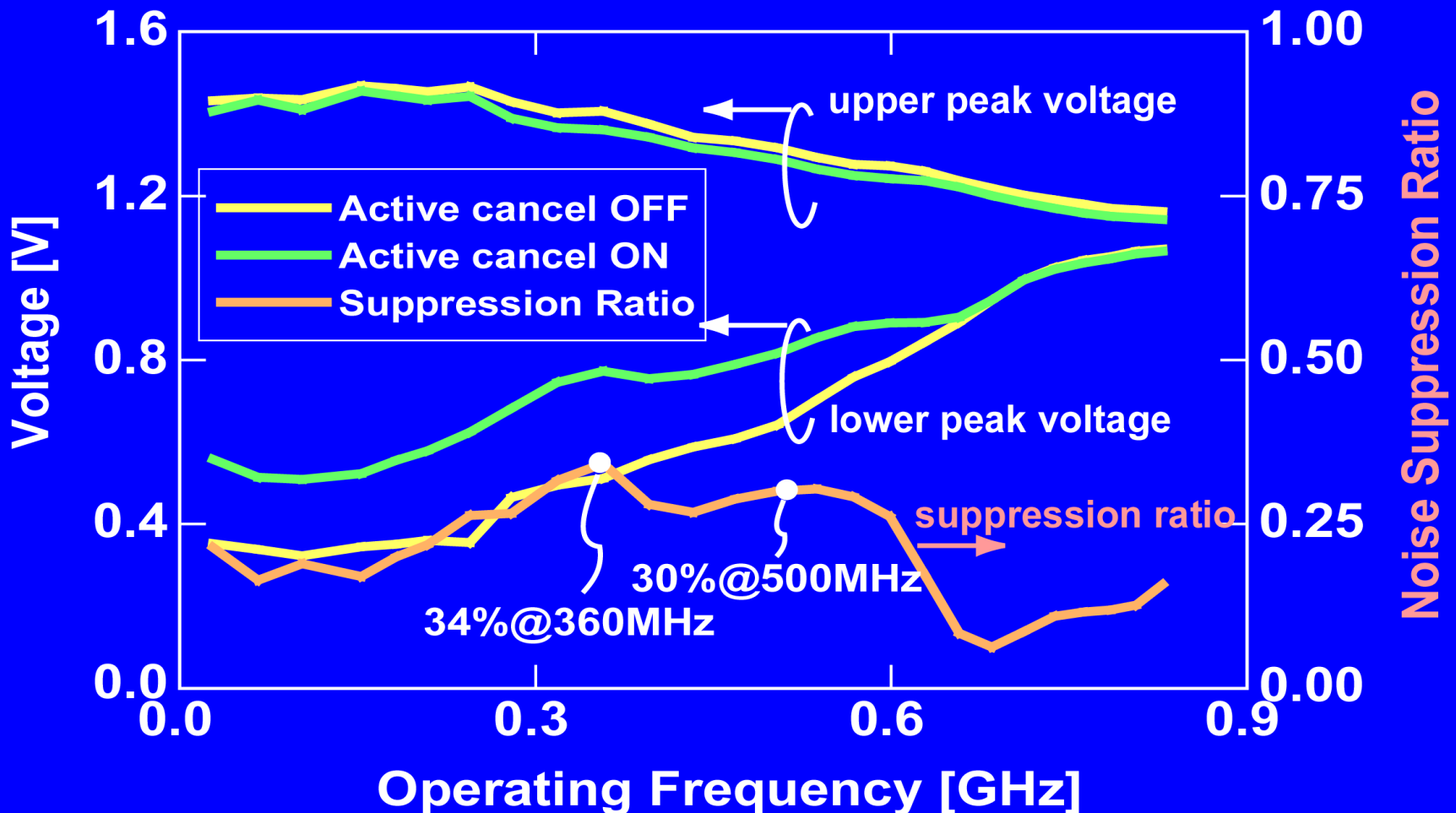
- ON, OFF means  $V_{dd\_Canceller}=3.3V, 0V$



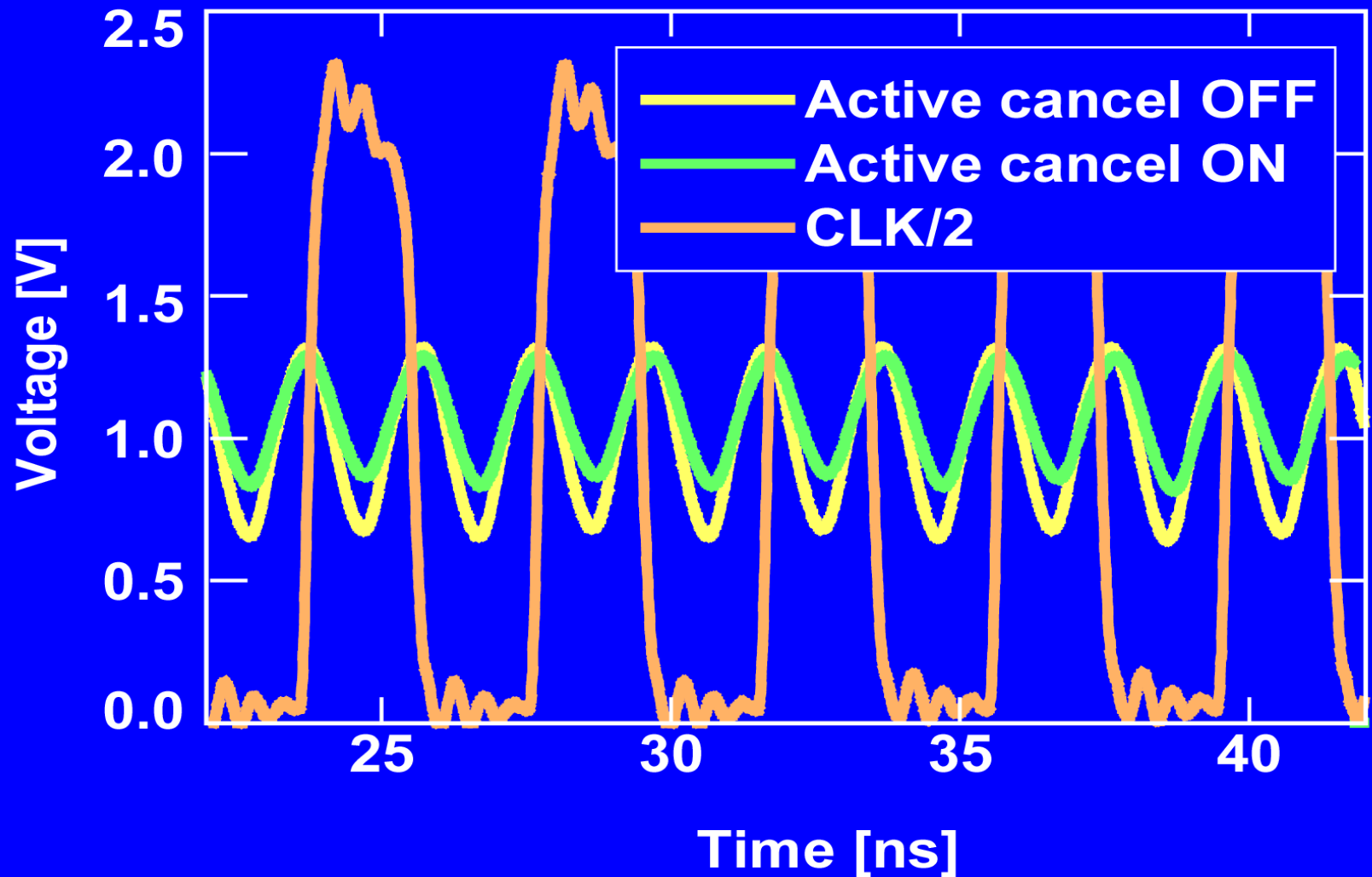
# Waveform (Random@500MHz)



# Frequency Dependence (repeat)

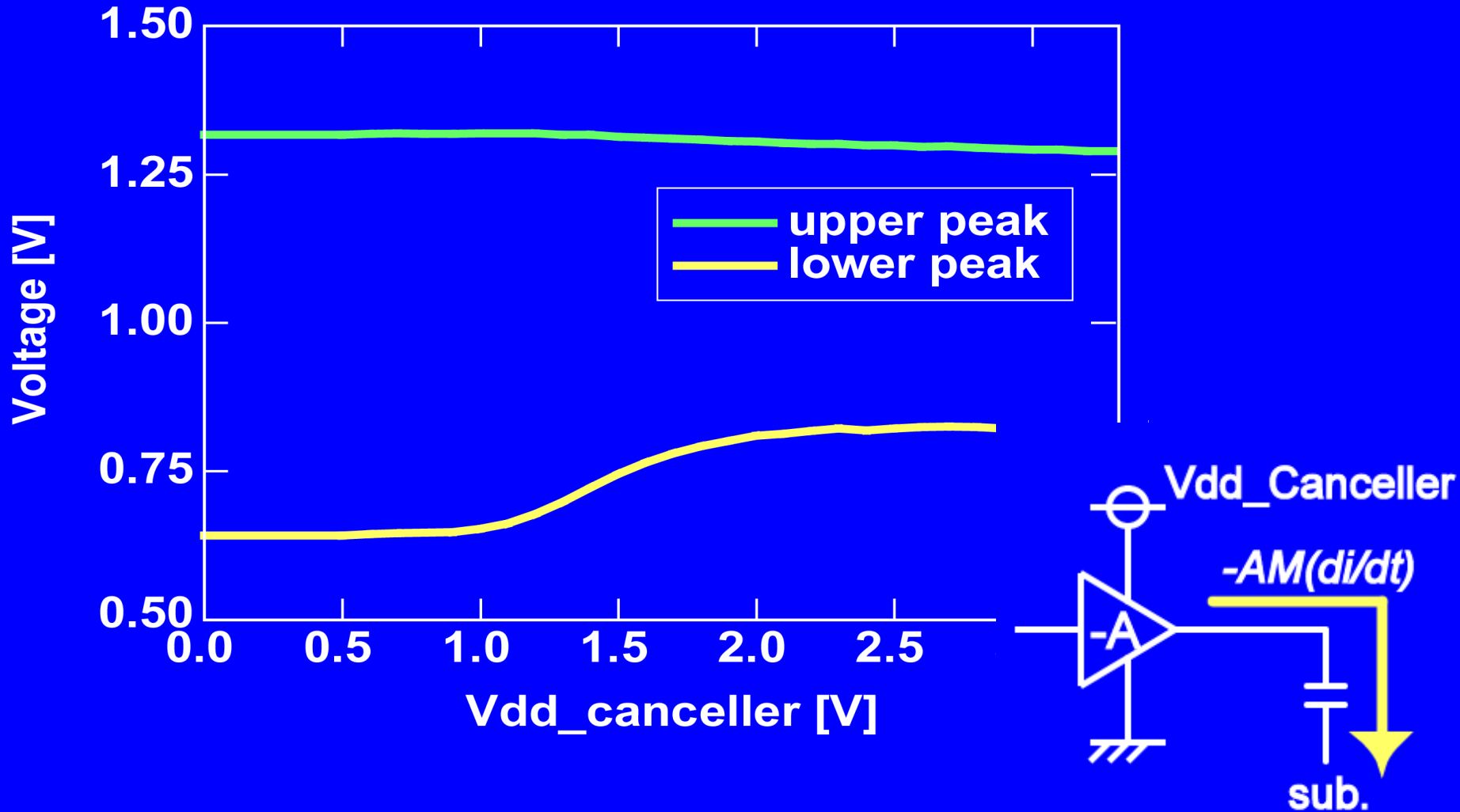


# Waveform (Repeat@500MHz)

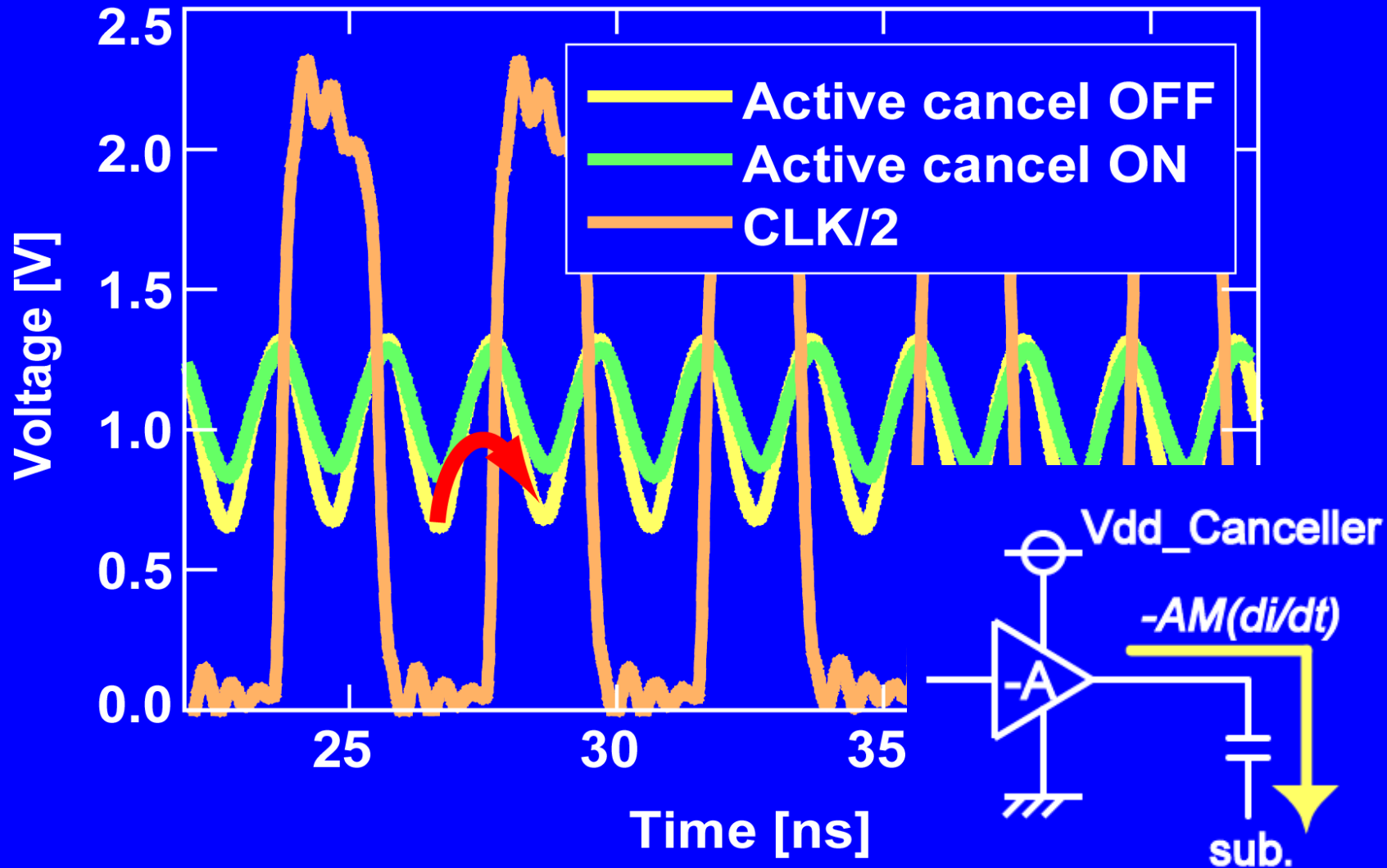




# Noise Amplitude Change

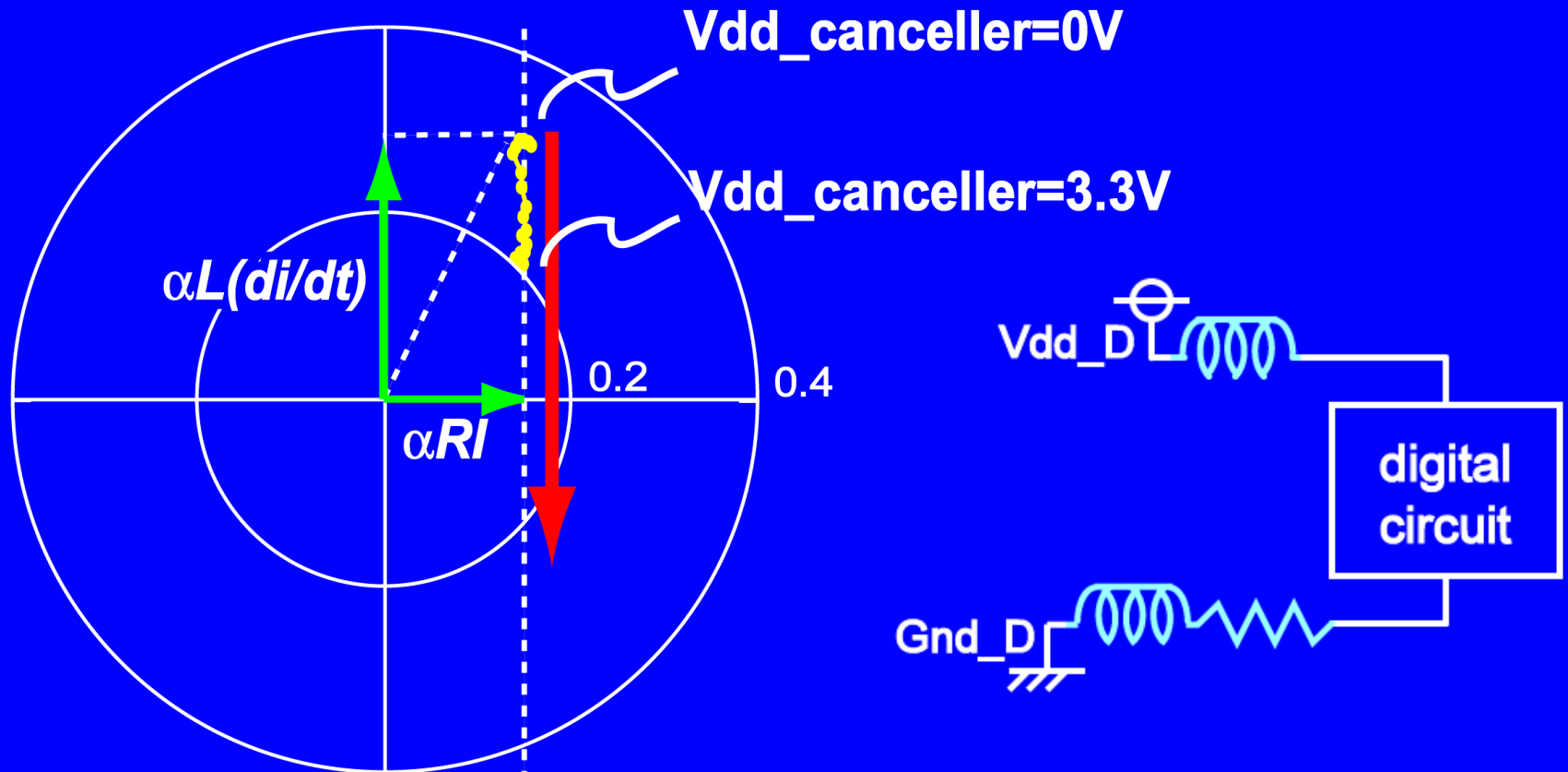


# Substrate Noise Change

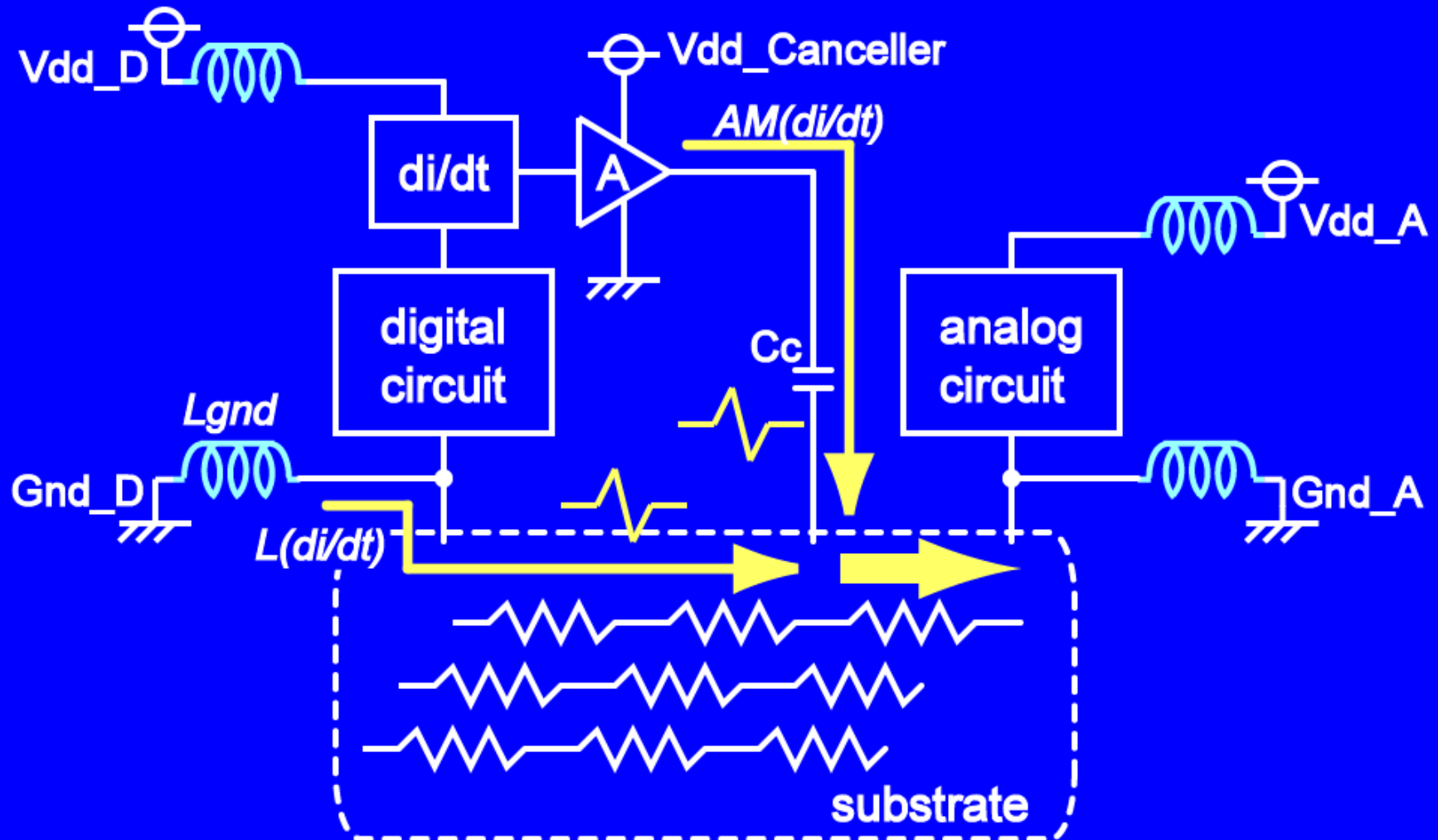


# Phasor of the Substrate Noise

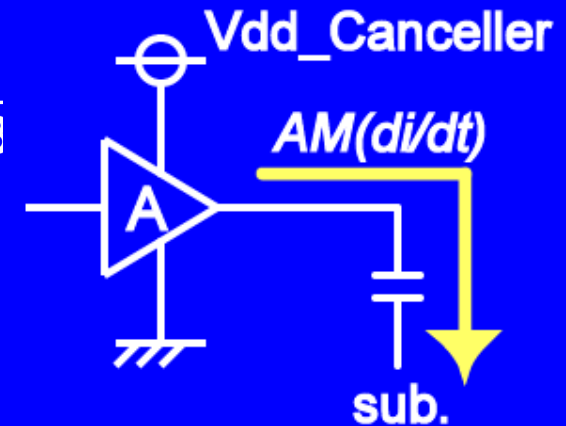
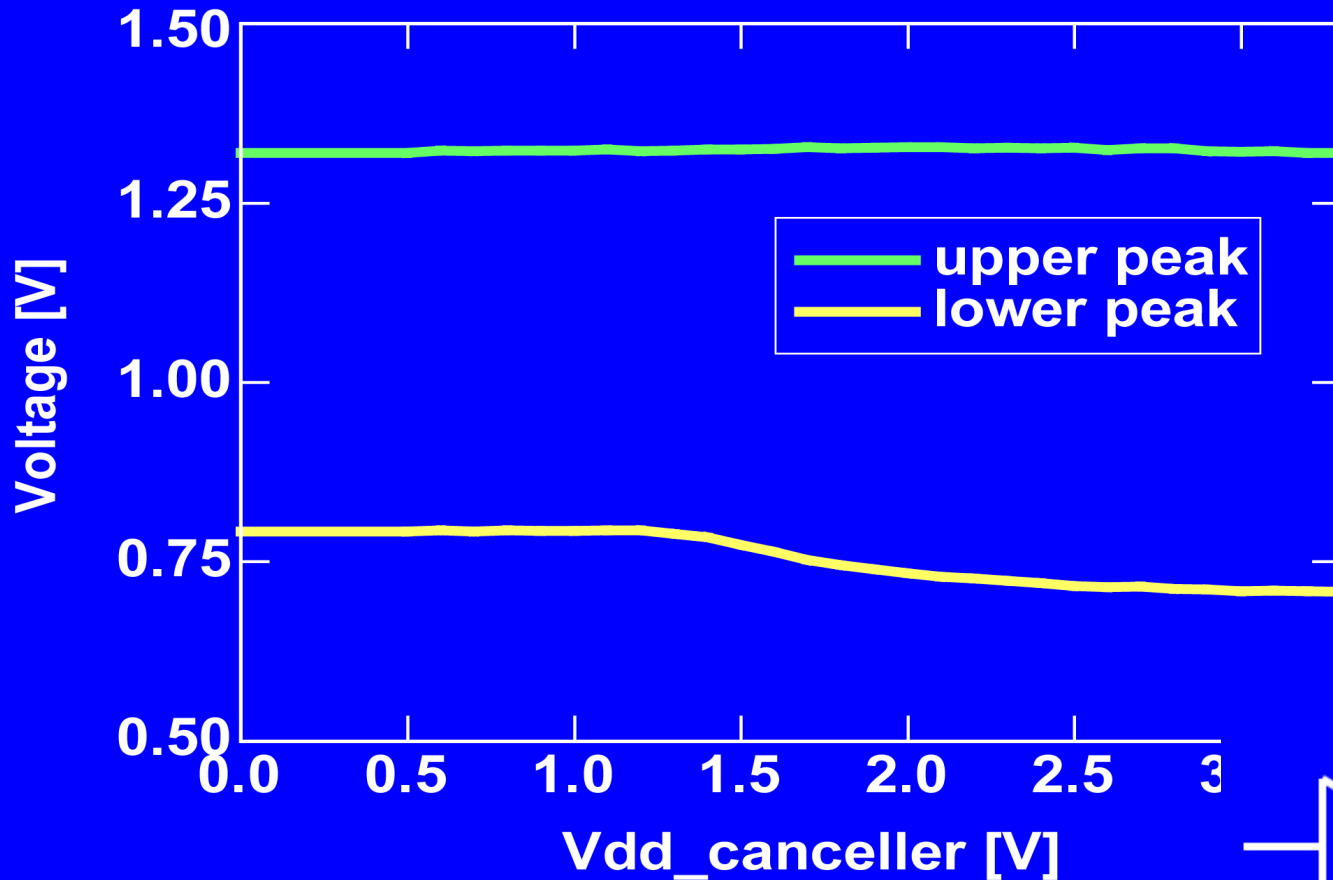
- 54% noise reduction would be achieved by optimizing the amplifier design



# In-phase Current Injection



# In-phase Current Injection



# Summary

---

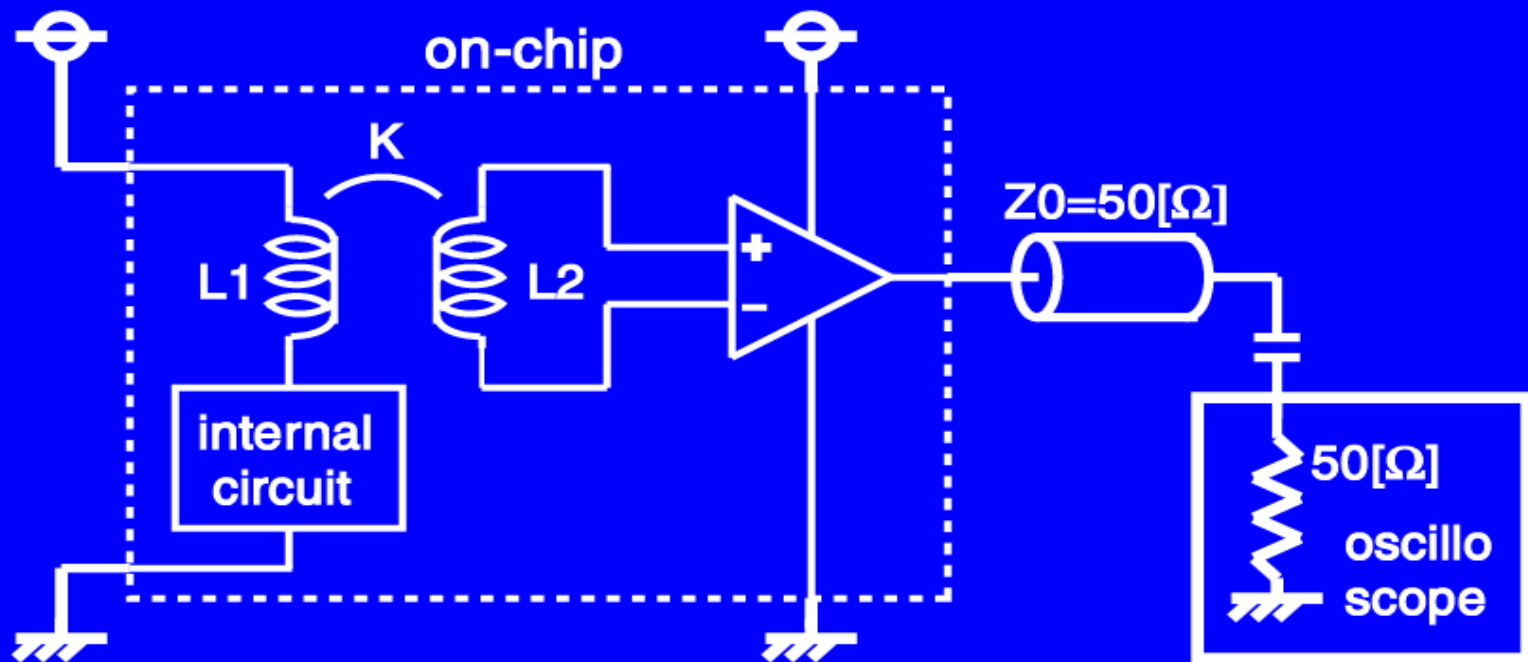
- **Feedforward active substrate noise cancelling technique is demonstrated**
- **A di/dt detector generates anti-phase signals, and injected into the substrate**
- **Measurement results show that 17% to 34% of the substrate noise reduction is achieved from 100MHz to 600MHz range**
- **Optimized injector design will enhance the noise suppression ratio up to 56%**

---

**Q&A**

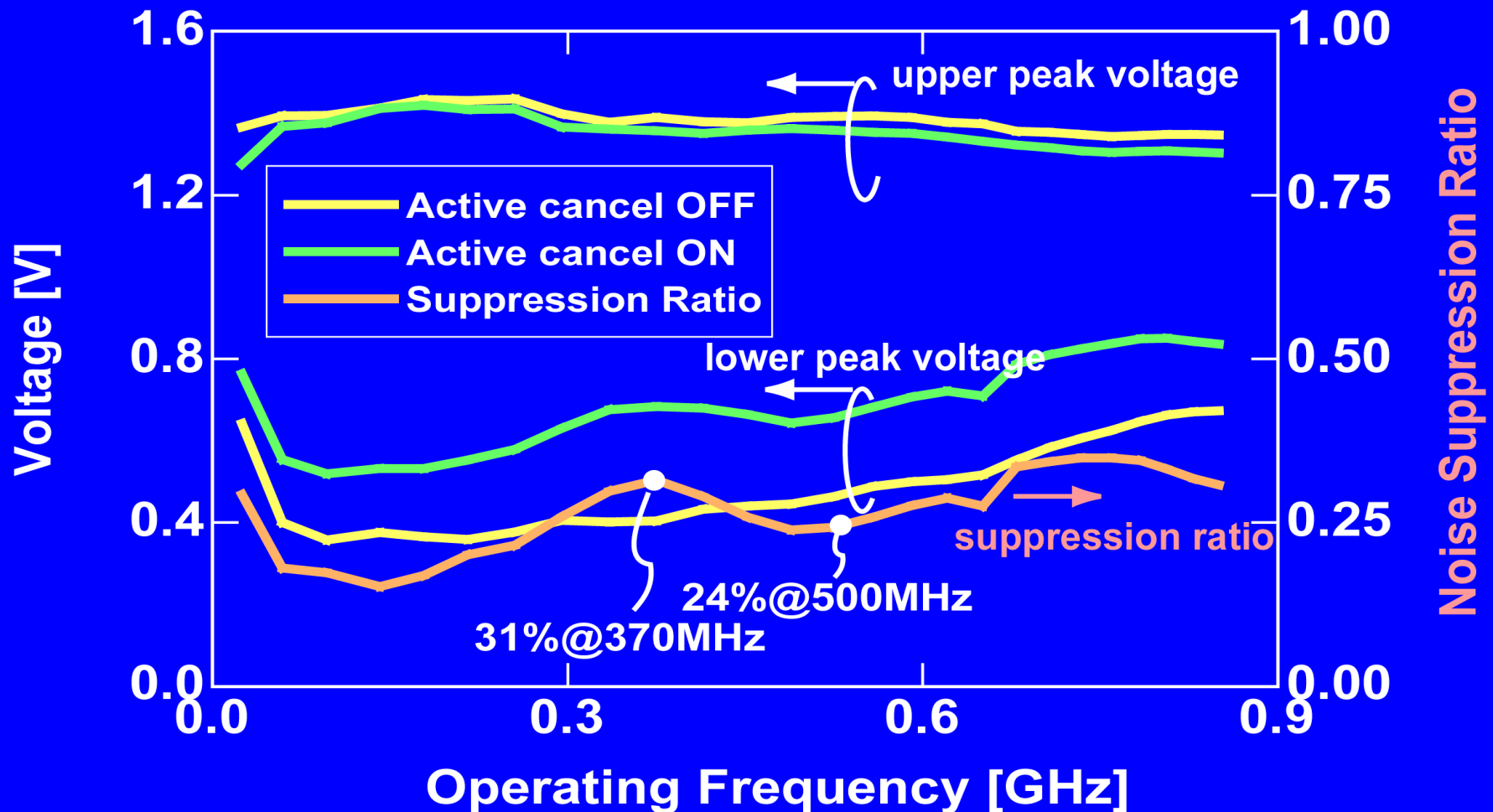
# di/dt Detector Block Diagram

- L2 picks up the di/dt, induce the voltage
- Amplifier amplifies/output the voltage





# Frequency Dependence (random)



# Overall Circuit

- Change the Gnd line impedance by the chip mount

